

**Search Notes**

Application No.

10/639,925

Examiner

Toan M. Le

**Applicant(s)**

PREIKSAS ET AL.

Art Unit

2863

**SEARCHED**

Class	Subclass	Date	Examiner
702	107	2/3/2005	TL
250	396R	2/2/2005	TL
250	201.3	2/3/2005	TL
359	383	2/3/2005	TL
359	17	2/3/2005	TL
382	255	2/3/2005	TL
Above	Updated	10/6/2005	TL
250	311	10/6/2005	TL
Above	Updated	12/22/2006	TL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Electron Microscope, Control, Index	2/3/2005	TL
Electron Microscope, Macro	2/11/2005	TL
Electron Microscope, Computer Control	2/11/2005	TL
East- See Search History Printout	10/6/2005	TL
702/107; 250/396R,201.3,311; 359/383,17; 382/255 (Electron Microscope Index Interpolate)	12/17/2006	TL
East- See Search History Printout	12/17/2006	TL
IEEE Xplore, Web search	12/22/2006	TL